## Searched



Application/Control No.

Applicant(s)/Patent Under Reexamination

10707496

NGUYEN ET AL.

Examiner

Kaplan, Hal I

Art Unit

2836

Class	Su	bClass Date	Examiner
307	43	10/24/2006	HK
307	65	10/24/2006	HK
307	80	10/25/2006	HK
307	84	10/25/2006	HK
307	85	10/25/2006	HK
307	86	10/25/2006	HK

## Search Notes



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Notes	Date	Examiner	
307/43,64,65,80,84,85,87 (consulted Robert DeBeradinis)	04/25/2006	HK	
361/20,21 (consulted Stephen W. Jackson)	04/25/2006	HK	
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